

ABSTRACT OF THE DISCLOSURE

A general method is given for screening laser diodes for electrostatic discharge, (ESD), damage. The laser diode may be selectively isolated from the laser driver so that a current-voltage (I-V), curve can be taken and then compared to curves taken previously on the same laser diode to ascertain the possibility of ESD damage. Presumably the initial I-V curve will be representative of the characteristics of that particular laser in the undamaged state. Such an initial curve may be supplied by the manufacturer and may be a curve specific to a particular laser diode. Comparison with a standard curve is not sufficient to determine ESD damage in the early stages of failure. Some embodiments focus on isolating the laser diode from the laser driver, storing the information locally in the transceiver, and providing some analysis resulting in flagging laser diodes showing changes that are indicative of ESD damage.

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